



# TEST REPORT

**Reference No.** ..... : WTF20F10077233S  
**Applicant** ..... : Mid Ocean Brands B.V.  
**Address** ..... : 7/F., Kings Tower, 111 King Lam Street, Cheung Sha Wan, Kowloon,  
Hong Kong  
**Manufacturer** ..... : 107961  
**Address** ..... : /  
**Product Name** ..... : RFID protective card in bamboo  
**Model No.** ..... : MO6200  
**Ratings** ..... : --  
**Standards** ..... : Customer requirements  
**Date of Receipt sample** ..... : 2020-10-26  
**Date of Test** ..... : 2020-10-28 to 2020-10-30  
**Date of Issue** ..... : 2020-11-03  
**Test Report Form No.** ..... : WST-133188-02A  
**Test Result** ..... : See the attached sheets

**Remarks:**

The results shown in this test report refer only to the sample(s) tested, this test report cannot be reproduced, except in full, without prior written permission of the company. The report would be invalid without specific stamp of test institute and the signatures of compiler and approver.

**Prepared By:**

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Compiled by:

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Approved by:

Jerry Mu / Manager



## List of test items:

No.	Test Items	Requirement + Test	Result
1	Anti-skimming test	Customer requirements	See below

## Subcontract

Whether parts of tests for the product have been subcontracted to other labs:

Yes  No

If Yes, list the related test items and lab information:

Test items: ---

Lab information: --

## Possible test case verdicts:

- test case does not apply to the test object.....: N

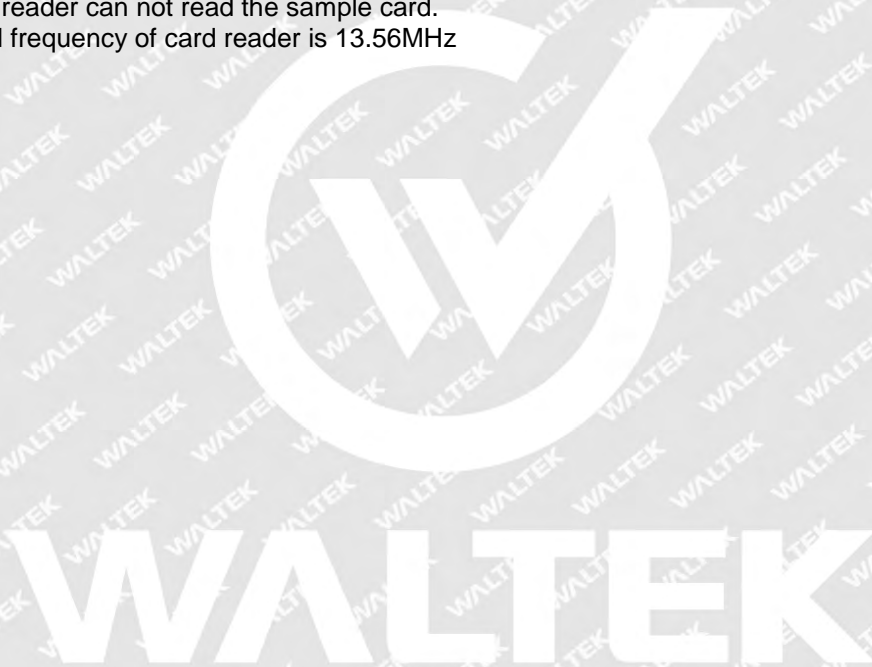
- test object does meet the requirement.....: P (Pass)

- test object does not meet the requirement.....: F (Fail)

## Remarks:

The card reader can not read the sample card.

The rated frequency of card reader is 13.56MHz



**Test Item:**

Anti-skimming test

**1.1 Test Environment**

Temperature: 23 °C Humidity: 50% RH

**1.2 Test procedure:**

- 1) Keep the IC card and the sample close together. Put the sample gradually close to the reading machine, to see how far the IC card could be read. Mark the distance A
- 2) Then the sample is separated from the IC card. And put this IC card gradually close to the reading machine, to see how far the IC card could be read. Mark the distance B.
- 3) Compare A and B

**1.3 Test result:**

Sample	No	Test position
1	B	40.1mm
	A	17.3mm
2	B	40.2mm
	A	18.1mm
3	B	40.0mm
	A	17.9mm
4	B	41.6mm
	A	17.5mm
5	B	40.9mm
	A	18.9mm

Remark: A – Distance of the IC card can be read with sample;

B – Distance of the IC card can be read without sample.

NG – Negative, cannot be read

0 – can be read when contact the machine



Photo 1 - Sample

===== End of Report =====

**WALTEK**